

Notice of References Cited

Application/Control No.

10/584,218

Applicant(s)/Patent Under
Reexamination
MIYACHI ET AL.

Examiner

Sean P. Cullen, Ph.D.

Art Unit

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2006/0068296 A1	03-2006	Nakagawa et al.	429/324
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	WO 2004051784 A1	06-2004	World Intellect	NAKAGAWA et al.	
	O					
	P					
	Q					
	R					
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	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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